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- Computer Security
- Information Access and User Interfaces
- High Performance Systems and Services
- Distributed Computing and Information Services
- Software Diagnostics and Conformance Testing

¹ At Boulder, CO 80303.

² Some elements at Boulder, CO.

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The Journal of Research of the National Institute of Standards and Technology features advances in measurement methodology and analyses consistent with the NIST responsibility as the nation's measurement science laboratory. It includes reports on instrumentation for making accurate and precise measurements in fields of physical science and engineering, as well as the mathematical models of phenomena which enable the predictive determination of information in regions where measurements may be absent. Papers on critical data, calibration techniques, quality assurance programs, and well-characterized reference materials reflect NIST programs in these areas. Special issues of the Journal are devoted to invited papers in a particular field of measurement science. Occasional survey articles and conference reports appear on topics related to the Institute's technical and scientific programs.

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